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<u>L22</u> 717/175,140,165.CCLS.	372	<u>L22</u>
<u>L21</u> 717/124,125,126,127.ccls.	639	<u>L21</u>
<u>L20</u> 702/123.ccls.	132	<u>L20</u>
<u>L19</u> 710/8.ccls.	872	<u>L19</u>
<u>L18</u> 714/38.ccls.	803	<u>L18</u>
<u>L17</u> 713/201.ccls.	1385	<u>L17</u>
<u>L16</u> 714/100.ccls.	28	<u>L16</u>
<i>DB=TDBD; PLUR=YES; OP=ADJ</i>		
<u>L15</u> ((program\$ or software\$ or application\$) near5 (verif\$ or test\$ or debug\$) and ((program interface) or api)and ((program interface) or api) near5 program\$ and (resource\$ or device\$) near4 constrai\$ and (disabl\$ near5 instal\$)	0	<u>L15</u>
<i>DB=DWPI; PLUR=YES; OP=ADJ</i>		
(program\$ or software\$ or application\$) near5 (verif\$ or test\$ or debug\$) and		

<u>L14</u>	((program interface) or api)and ((program interface) or api) near5 program\$ and (resource\$ or device\$) near4 constrai\$ and (disabl\$ near5 instal\$)	1	<u>L14</u>
	<i>DB=JPAB; PLUR=YES; OP=ADJ</i>		
<u>L13</u>	((program interface) or api)and ((program interface) or api) near5 program\$ and (resource\$ or device\$) near4 constrai\$ and (disabl\$ near5 instal\$)	0	<u>L13</u>
	<i>DB=EPAB; PLUR=YES; OP=ADJ</i>		
<u>L12</u>	((program interface) or api)and ((program interface) or api) near5 program\$ and (resource\$ or device\$) near4 constrai\$ and (disabl\$ near5 instal\$)	0	<u>L12</u>
	<i>DB=USOC; PLUR=YES; OP=ADJ</i>		
<u>L11</u>	((program interface) or api)and ((program interface) or api) near5 program\$ and (resource\$ or device\$) near4 constrai\$ and (disabl\$ near5 instal\$)	0	<u>L11</u>
	<i>DB=PGPB; PLUR=YES; OP=ADJ</i>		
<u>L10</u>	((program interface) or api)and ((program interface) or api) near5 program\$ and (resource\$ or device\$) near4 constrai\$ and (disabl\$ near5 instal\$)	8	<u>L10</u>
	<i>DB=USPT; PLUR=YES; OP=ADJ</i>		
<u>L9</u>	L6 and l2	51	<u>L9</u>
<u>L8</u>	L6 and l3	0	<u>L8</u>
<u>L7</u>	L6 and l4	0	<u>L7</u>
<u>L6</u>	717/124,126,127.ccls.	542	<u>L6</u>
<u>L5</u>	L4 and (disabl\$ near5 instal\$)	1	<u>L5</u>
<u>L4</u>	L3 and (instal\$ near5 (resource\$ or device\$))	22	<u>L4</u>
<u>L3</u>	L2 and (resource\$ or device\$) near4 constrai\$	61	<u>L3</u>
<u>L2</u>	L1 and ((program interface) or api) near5 program\$	1719	<u>L2</u>
<u>L1</u>	(program\$ or software\$ or application\$) near5 (verif\$ or test\$ or debug\$) and ((program interface) or api)	2787	<u>L1</u>

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	(program\$ or software\$ or application\$) near5 (verif\$ or test\$ or debug\$) and		
<u>L15</u>	((program interface) or api)and ((program interface) or api) near5 program\$	0	<u>L15</u>
	and (resource\$ or device\$) near4 constrai\$ and (disabl\$ near5 instal\$)		
	<i>DB=DWPI; PLUR=YES; OP=ADJ</i>		
	(program\$ or software\$ or application\$) near5 (verif\$ or test\$ or debug\$) and		
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	and (resource\$ or device\$) near4 constrai\$ and (disabl\$ near5 instal\$)		
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<u>L5</u>	L4 and (disabl\$ near5 instal\$)	1	<u>L5</u>
<u>L4</u>	L3 and (instal\$ near5 (resource\$ or device\$))	22	<u>L4</u>
<u>L3</u>	L2 and (resource\$ or device\$) near4 constrai\$	61	<u>L3</u>
<u>L2</u>	L1 and ((program interface) or api) near5 program\$	1719	<u>L2</u>
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1 [Fast detection of communication patterns in distributed executions](#)

Thomas Kunz, Michiel F. H. Seuren

 November 1997 **Proceedings of the 1997 conference of the Centre for Advanced Studies on Collaborative research**

 Full text available: [pdf\(4.21 MB\)](#)

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Understanding distributed applications is a tedious and difficult task. Visualizations based on process-time diagrams are often used to obtain a better understanding of the execution of the application. The visualization tool we use is Poet, an event tracer developed at the University of Waterloo. However, these diagrams are often very complex and do not provide the user with the desired overview of the application. In our experience, such tools display repeated occurrences of non-trivial commun ...

2 [Safely executing untrusted code: Model-carrying code: a practical approach for safe execution of untrusted applications](#)

R. Sekar, V.N. Venkatakrishnan, Samik Basu, Sandeep Bhatkar, Daniel C. DuVarney

 October 2003 **Proceedings of the nineteenth ACM symposium on Operating systems principles**

 Full text available: [pdf\(301.30 KB\)](#)

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This paper presents a new approach called *model-carrying code* (MCC) for safe execution of untrusted code. At the heart of MCC is the idea that untrusted code comes equipped with a concise high-level model of its security-relevant behavior. This model helps bridge the gap between high-level security policies and low-level binary code, thereby enabling analyses which would otherwise be impractical. For instance, users can use a fully automated verification procedure to determine if the code ...

Keywords: mobile code security, policy enforcement, sand-boxing, security policies

3 [Parallel execution of prolog programs: a survey](#)

Gopal Gupta, Enrico Pontelli, Khayri A.M. Ali, Mats Carlsson, Manuel V. Hermenegildo

 July 2001 **ACM Transactions on Programming Languages and Systems (TOPLAS)**, Volume 23 Issue 4

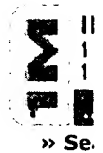
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Clarke, D.; Lee, I.;

Test Conference, 1996. Proceedings., International , 20-25 Oct. 1996

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2 **The use of model-based test requirements throughout the product life cycle**
Bukata, E.; Davis, D.C.; Shombert, L.;

Aerospace and Electronic Systems Magazine, IEEE , Volume: 15 , Issue: 2 , February 2000

Pages:39 - 44

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3 **An integrated approach to verification, validation, and accreditation of models and simulations**
Caughlin, D.;

Simulation Conference Proceedings, 2000. Winter , Volume: 1 , 10-13 Dec. 2000

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[\[Abstract\]](#) [\[PDF Full-Text \(776 KB\)\]](#) IEEE CNF
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Ostroff, J.S.;

Industrial-Strength Formal Specification Techniques, 1995. Proceedings., Workshop on , 5-8 April 1995

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